

Improved Measurement of the π^+ Lifetime Experiment S2307

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Collaboration

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Balance of early-career and experienced scientists. Multiple participants were part of the MuLan collaboration (muon lifetime experiment).

C. B.-Champagne is a PIF & NIF expert, G. Morris is a TRIUMF's μ SR beam lines expert, and T. Numao led the past TRIUMF measurement.

Charged Pion Lifetime

The PDG 2022 average is $\tau_{\pi}=26.033\pm0.005$ ns ($\delta au/ au=0.02\%$)

π^{\pm} MEAN LIFE

Measurements with an error $>~0.02\times 10^{-8}\,s$ have been omitted.

VALUE (1	.0 ⁻⁸ s)	DOCUMENT ID		TECN	CHG	COMMENT
2.6033	± 0.0005 OUR AVERAGE	Error includes	scale f	actor of	1.2.	
2.60361	± 0.00052	¹ KOPTEV	95	SPEC	+	Surface μ^+ 's
2.60231	$\pm 0.00050 \pm 0.00084$	NUMAO	95	SPEC	+	Surface μ^+ 's
2.609	± 0.008	DUNAITSEV	73	CNTR	+	
2.602	± 0.004	AYRES	71	CNTR	\pm	
2.604	± 0.005	NORDBERG	67	CNTR	+	
2.602	± 0.004	ECKHAUSE	65	CNTR	+	
ullet $ullet$ $ullet$ We do not use the following data for averages, fits, limits, etc. $ullet$ $ullet$						
2.640	± 0.008	² KINSEY	66	CNTR	+	
1 KOPTEV 95 combines the statistical and systematic errors; the statistical error domi-						
_ nates.						
² Systematic errors in the calibration of this experiment are discussed by NORDBERG 67						

TRIUMF experiment \rightarrow M. C. Fujiwara, T. Numao, A. J. Macdonald, G. M. Marshall, A. Olin, Phys. Rev. D **52** (1995) 4855

Charged Pion Lifetime & Lepton Universality

Powerful test of the electron-muon universality \rightarrow Precisely measure

$$R_{e/\mu} = rac{\Gamma\left(\pi^+
ightarrow e^+
u(\gamma)
ight)}{\Gamma\left(\pi^+
ightarrow \mu^+
u(\gamma)
ight)} \propto f(m_\pi, m_\ell) \cdot rac{g_e}{g_\mu} \; ,$$

where g_e and g_{μ} are the electron and muon couplings to the W boson.

The uncertainty on the SM prediction ($g_e = g_\mu$) is less than 0.01%:

$$R_{e/\mu}^{
m SM} = (1.23524 \pm 0.00015) imes 10^{-4}$$

V. Cirigliano et al., Phys. Rev. Lett. 99 (2007) 231801 V. Cirigliano et al., JHEP 10 (2007) 005 W. J. Marciano et al., Phys. Rev. Lett. 71 (1993) 3629

Rich experimental history at TRIUMF (PIENU '86, '94, '15). PDG average:

$$R_{
m e/\mu}^{
m PDG} = (1.2327 \pm 0.0023) imes 10^{-4}$$
 .

New measurement planned by the PIONEER collaboration, approved at PSI \rightarrow Reduce the $R_{e/\mu}$ experimental uncertainty to 0.01%.

Impact of τ_{π} on the $R_{e/\mu}$ Error Budget

Basic principle, count $\pi \to e$ and $\pi \to \mu \to e$ events, τ_{π} enters in the ratio:

$$R_{e/\mu} = \frac{\lambda_{\mu}}{\lambda_{\pi} - \lambda_{\mu}} \frac{N_{\pi e}}{De^{\lambda_{\mu}t_{s}} - N_{\pi\mu e}} \left(1 - e^{-(\lambda_{\pi} - \lambda_{\mu})t_{s}}\right)$$

E. Di Capua et al, Phys. Rev. 133 (1967) B1333

Impact on PIENU syst. uncertainty: $\delta R = \pm 0.57 \times 10^{-8} (\delta R/R = 0.005\%)$

In the PIONEER context, $\delta \tau_{\pi}/\tau_{\pi}$ becomes relevant:

	PIENU 2015	PIONEER Estimate
Error Source	%	%
Statistics	0.19	0.007
Tail Correction	0.12	$<\!0.01$
t_0 Correction	0.05	$<\!0.01$
Muon DIF	0.05	0.005
Parameter Fitting	0.05	$<\!0.01$
Selection Cuts	0.04	$<\!0.01$
Acceptance Correction	0.03	0.003
Total Uncertainty	0.24	≤ 0.01

(Modern experiments are fitting a model to the time spectra.)



Proposed Experimental Method

Take advantage of TRIUMF's micro-bunched proton beam.



Extract the π^+ lifetime from the surface-muon yield of a production target.

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TRIUMF's Beam Structure

Cyclotron driving freq. is 23 MHz (one bunch every \approx 43.3 ns) \rightarrow The inspection window is too short for a precise τ_{π} measurement.

But, the "1:5 selector", installed on the injection line, allows to suppress 4/5 bunches, lengthening the inspection period to \approx **215 ns**.



Understanding the beam leakages is key for this experiment.

M20 Beamline

TRIUMF's M9A, M15 and M20 (μ SR) have the desired characteristics:

- Tuned to $P \approx 30 \text{ MeV}/c$, thin vacuum windows,
- DC separators for positrons rejection (500:1),
- Small beam spot at the final focus point.



G4beamline model of M20 – G. Morris and TRIUMF's μ SR group.

We propose a measurement campaign to determine precisely (a) $\delta P/P$, (b) the positron contamination, and (c) the surface- μ^+ rate with the slits in the extended position.

Conceptual Detector Layout

Baseline \rightarrow Telescope made of 4 thin plastic scintillator counters, each read-out by a SiPMs. Pulse timing and amplitude (dE/dx) recorded by an ADC.



As an example, Numao et al. used 0.25, 0.13, 0.50, and 10 mm thick counters for C1, C2, C3 and C4, respectively. Final thicknesses will be fine-tuned to the beam characteristics.

Statistical Uncertainty - Fitting Interval

The 1:5 selector is essential.



All subsequent plots are based on 2 \times 10⁸ $\pi^+ \to \mu^+ \nu$ events and a 150 ns fitting interval.

Systematic Uncertainties - Overview



 \rightarrow Keep the contamination fraction of the μ^+ sample below 10⁻⁵.

1:5 Selector and Beam leakages

Possible online monitoring of the 1:5 selector performance in BL2C.



Arrangements made to measure the *beam leakage* directly with protons at PIF & NIF.

Systematic Uncertainty – Positrons & Cloud Pions

The positron background has two components:

- ▶ Prompt, $\pi^0 \rightarrow \gamma(\gamma \rightarrow e^+e^-) \rightarrow$ Discard the first 15 ns after the proton burst,
- ▶ Flat, $\mu^+ \rightarrow e^+ \nu \bar{\nu} (\tau_\mu \gg \tau_\pi) \rightarrow$ Negligible, stopping rate in C3, dE/dx.

Positrons in the beam are further suppressed by the DC separator (factor 500:1).

A cloud of (slow) π^+ hang around the target and decay into $\mu^+ {\rm s},$ some of which are accepted by the beamline.

This needs to be measured, two options:

- Look at the μ^+ spectrum just above the surface- μ^+ edge and extrapolate down,
- Look at the μ^- spectrum, it requires inverting the beamline polarity.

Systematic Uncertainty - Time of flight

Keep the surface- μ arrival time dispersion < 5 ns.

- $\delta P/P$ will be measured, 1% (FWHM) \rightarrow 1.4 ns,
- Path variations will be studied with a G4beamline simulation.



Summary – Projected Systematic Uncertainties

The pion diffusion and pion cloud component estimates are tentatively based on Numao et al.

Sources	Uncertainty estimates (ps)		
Beam leakage	< 0.5		
Muons from the π^+ cloud	≤ 2		
Time of flight	< 0.5		
Positrons	< 0.4		
Pions	< 0.1		
Pion diffusion	≤ 0.3		
Total	< 2.2		

We will use a blind analysis method.

Timeline & Beamtime Request

We propose a two-step approach:

- 1. Beam extinction and μ SR beamline studies. This can be started anytime.
- 2. Once those studies are done, organize the π^+ lifetime measurement.

Activity	Requested Allocation	1:5 Selector	PIF & NIF
Beam extinction studies	Machine devel.	Yes	Yes
Beamline studies	3 shifts	No	No
Detector setup	2 shifts	No	Yes
Pion lifetime	18 shifts	Yes	Yes

Summary

The PIONEER experiment will push the boundaries of the lepton universality tests in the coming years.

A 0.01% π^+ lifetime measurement is an important piece of the puzzle.

TRIUMF provides an ideal environment to improve the π^+ lifetime.

- 1:5 selector allows to extend the burst period,
- Extensive local μ SR expertise.

The 0.01% precision goal looks achievable with a week of beam time.

- Collect a > 2 × 10⁸ sample of $\pi^+ \rightarrow \mu^+ \nu$ events,
- Dedicated studies for the pion cloud background component,
- Online beam extinction monitoring.



1:5 Selector



J. Beveridge et al., IEEE Trans. Nucl. Sci. NS-22 (1975) 1707

Sample Size



We need to collect a minimum of $2 \times 10^8 \pi^+ \rightarrow \mu^+ \nu$ events. Assuming a surface- μ^+ rate of 10 kHz and a detection efficiency of $\varepsilon = 0.5$, it would take about 11 hours (with a 100% cyclotron duty cycle).

Previous Measurements Based on Surface- μ^+ s

The two most recent experiments, conducted by Koptev et al. (JETP Lett. **61** (1995) 877) and Numao et al. (Phys. Rev. D **52** (1995) 4855), used momentum-analyzed surface-muons. [‡]





Numao et al., **150 ns** examination window, systematics limited. $\tau_{\pi}^{+} = 26.0231 \pm 0.0050 \pm 0.0084$

[‡]Older experiments examined the $\pi^+ \rightarrow \mu^+$ or $\pi^+ \rightarrow \mu^+ \rightarrow e^+$ (stopped pions) sequence, or the π^{\pm} attenuation along a decay volume, see PDG for details.

DAQ System

We will digitize the PMT/SiPM waveforms, while the trigger definition will be based on analog signal coincidence logic. The acquisition can run on a standard PC and will be controlled by the MIDAS software package.

Main requirements:

- Able to digitize 6 channels (counters + cyclotron's RF pulses),
- ADC sampling rate \geq 500 MS/s,
- ► ADC resolution ≥ 10-bit,
- Good clock stability (e.g. SRS CG635),
- Able to sustain a 10 kHz trigger rate (average).



Data Blinding Procedure

Current thought: Make the exact master clock frequency *F* unknown to the experimenters ($F \rightarrow \alpha F$). The hidden parameter α is needed to convert the final τ_{π} value to seconds.



where *i* is the ADC sample index and F_s is the ADC sampling frequency (which is set by the master clock).

Surface-muon Beams

Muon beam formed by the decay of pions that stops near the surface of a production target.

A. E. Pifer, T. Bowen, K. R. Kendall, NIM 135 (1976) 39

- Maximum μ^+ kinetic energy 4.1 MeV \rightarrow High stopping density,
- Well defined source which can be imaged at the final focus.



Charged Pion Decay – Formulae

At first order, the $\pi^+ \rightarrow \ell^+ \nu$ decay rate can be written as:

$$\Gamma \left(\pi^+ o \ell^+
u
ight) = rac{G_F^2 \left| V_{ud}
ight|^2 f_\pi^2}{4\pi} m_\pi m_\ell^2 \left(1 - rac{m_\ell^2}{m_\pi^2}
ight)^2 \; ,$$

where, G_F is the Fermi constant; V_{ud} is the CKM matrix element; and f_{π}^2 is the pion form factor.

See e.g. V. Cirigliano et al., JHEP 10 (2007) 00

The $\pi^+ \rightarrow \pi^0 e^+ \nu$ decay rate can be written as:

$$\Gamma\left(\pi^+ o \pi^0 e^+
u
ight) = rac{G_F^2 \left|V_{ud}
ight|^2}{30\pi^3} \left(1-rac{\Delta}{2m_{\pi^+}}
ight)^3 \Delta^5 f(arepsilon,\Delta) \left(1+\delta
ight) \; ,$$

where $\Delta = m_{\pi^+} - m_{\pi^0}$; $\varepsilon = m_e^2/\Delta$; and δ encodes the radiative corrections. See A. Sirlin, 1978, for the form of f.

A. Sirlin, Rev. Mod. Phys 50 (1978) 573

Charged Pion Lifetime & V_{ud}

The tension in the CKM matrix first-row unitarity relation could be connected to a violation of the lepton flavor universality.

[arXiv:2111.05338]



The CKM matrix element V_{ud} can be cleanly extracted from the pion beta decay branching ratio \mathcal{B} :

$$\Gamma\left(\pi^+ o \pi^0 e^+
u
ight) = rac{\mathcal{B}\left(\pi^+ o \pi^0 e^+
u
ight)}{ au_{\pi}} \propto \left|V_{ud}
ight|^2 \; .$$

The experimental \mathcal{B} , $(1.036 \pm 0.006) \times 10^{-8}$, is not competitive (red strip).

D. Pŏcanić et al., Phys. Rev. Lett. 93 (2004) 181803

In a second phase, PIONEER plans to improve $\mathcal{B}(\pi^+ \to \pi^0 e^+ \nu)$. A new π^+ lifetime measurement is needed to achieve the best precision on V_{ud} .

Numao et al. Systematic Uncertainties

TABLE I. Systematic uncertainties.

Sources	Uncertainties (ns)		
Beam leakage, ^a slow π^{a}	0.0083		
Prompt positron background	0.0002		
Flat positron background	0.0003		
Pion background	0.0002		
Extra muons	0.0001		
Other pion sources	0.0001		
Diffusion	0.0003		
Total uncertainty	0.0084		

^aIncluded in the fit.

Systematic Uncertainty – Beam leakage – Example

